FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. BE 9197	SERIAL NO. 09/831525
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary) (37 CFR 1.98(b)	APPLICANT Romain DESPLATS and Philippe PERDU	
	FILING DATE May 10, 2001	GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Cb	AA	5,321,354	06/94	OOSHIMA et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
Cb	AJ	EP 0 785 513	07/97	Europe			yes
	AK						
	AL						
	AM						
	AN						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

	AO	
	AP	

EXAMINER C Burott	DATE CONSIDERED 1-20-04

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form Y&T (3/94)

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. BE 9197	SERIAL NO. 09/831,525
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		APPLICANT Romain DESPLATS et al.	
37 CFR 1.98(b)		FILING DATE May 10, 2001	GROUP 2184

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
CB	AA	5,703,492	12-97	Nakamura et al.			
CB	AB						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
CB	AC						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

CB	AD	May et al. "Dynamic Fault Imaging of VSLI Random Logic Devices", IEEE, International Reliability Physics Symposium, pp. 95-108, 1984.
CB	AE	Kuji et al. "E-beam Static Fault Imaging with a CAD Interface and Its Application to Marginal Fault Diagnosis," IEICE Transactions on Electronics, Vol. E77-C, No. 4, pp. 552-559, 1994.
CB	AF	Nakamae et al. "Efficient Dynamic Fault Imaging by Fully Utilising CAD Data in CAD-linked Electron Beam Test Systems," IEICE Transactions on Electronics, Vol. E77-C, No. 4, pp. 546-551, 1994.
CB	AG	Nakamura et al. "LSI Fast Fault Localisation by Continuously Gated Fault Imaging Method," NEC Research & Development, Vol. 35, No. 3, pp. 269-277, 1994.
CB	AH	GERAUD-LIRIA et al. "Failure Analysis by Dynamic Voltage Contrast Development of a Semi-Automatic System," ISTFA 1987, Los Angeles, pp. 67-73.
CB	AI	PERDU. "Etude de circuits integres par contraste de potentiel : analyse des phenomenes de charge induits dans la couche de passivation," These de doctorat de l'UNIVERSITE PAUL SABATIER, No. 1740, pp. 37-50, 1994.
CB	AJ	Desplats et al. "High Speed Failure Localization With a New Application of I_{DDQ} Testing" May 25, 1998.
CB	AK	Desplats et al. "Shorter Failure Analysis Using a New Application of I_{DDQ} for Defect Localization in ICs," September 1998

EXAMINER	DATE CONSIDERED
C. Burt	*1-20-04*

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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